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International Conference on Applications and Techniques of Small-Angle Scattering
Argonne National Laboratory, 26–29 October 1987

This issue of the *Journal of Applied Crystallography* contains, along with normal contributed papers in various fields, 28 invited papers and 15 contributed papers from the International Conference on Applications and Techniques of Small-Angle Scattering.

This conference, organized by J. E. Epperson and P. Thiyagarajan and sponsored by the International Union of Crystallography, was held at Argonne National Laboratory, Argonne, IL, USA on 26–29 October 1987. The local committee, consisting of B. Brown, J. E. Epperson, D. Hoffmann and P. Thiyagarajan, brought together 140 scientists from 13 countries. A total of 34 invited papers and 33 contributed posters were presented.

A major goal of this conference was to provide a broad overview and then in-depth reviews of various aspects of small-angle scattering. Sincere thanks are extended on behalf of the conference organizers to all the authors for helping to realize this goal.

The present Proceedings were handled, with the usual stringent editorial requirements of *J. Appl. Cryst.*, by Gernot Kostorz, who is now terminating his nine-year-long activity as Co-editor of *J. Appl. Cryst.* Sincere thanks are extended to him on behalf of the International Union of Crystallography, the conference organizers and myself. Thanks are also due to F. Trouw for acting as liaison in collecting the manuscripts.

I trust the quicker authors will not regret the slight delay their manuscripts incurred. The reward is a volume that contains a lot of exciting science in this area of small-angle scattering, in a range of fields extending from biology to metallurgy, and is an impressive tribute to the improvements in techniques and in understanding that have occurred over the last few years.

I am sure all our readers will enjoy and benefit from this special issue now and over many years.

MICHEL SCHLENKER
Editor of *Journal of Applied Crystallography*